

25th International Conference on
Noise and Fluctuations

ICNF 2019

Proceedings

18 - 21 June 2019

EPFL Neuchâtel campus - Neuchâtel, Switzerland

Hosted by:

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Table of contents

Schedule at Glance	ii
Introduction	iii
Chairs & Committees	iv
Keynote Speakers	v
Shoji Kawahito	v
Alper Demir	vi
Enrico Rubiola	vii
Alexander Balandin	viii
Conference Technical Program	ix
Author index	361



SCHEDULE AT GLANCE



Introduction

The International Conference on Noise and Fluctuations (ICNF) is a biennial event that brings together researchers interested in theoretical and experimental aspects of fluctuations across a wide spectrum of scientific and technological fields. Since the development of the theory of Brownian motion, the science of fluctuation has been one of the most important parts of physics. The investigation of noise and fluctuation is indispensable for the understanding of the physical processes in various microscopic and macroscopic systems.

This conference will be a great opportunity for noise researchers operating in very different areas of scientific and technological endeavor to come together and create the basis for continued and renewed cross-fertilization and collaboration. The International Conference on Fluctuation Phenomena started in 1968 and moved all over the world.

For the first time the conference is taking place in Switzerland: the 25th edition (ICNF 2019) will be held in Neuchâtel (Switzerland), from June 18 to June 21, 2019.

About Neuchâtel

Neuchâtel is located on the northwestern shore of the Lake of Neuchâtel, in West Switzerland. On the side of the Jura Mountains, the environment is characterized by remote, windswept settlements and deep, rugged valleys. Neuchâtel is also in the heartland of the celebrated Swiss watchmaking industry.

EPFL

The Ecole Polytechnique Fédérale de Lausanne (EPFL) was founded in 1853 and became a national school in 1969. It is considered to be among the world's most prestigious universities of technology.

EPFL Neuchâtel campus

At the heart of the Microcity pole of innovation, the Canton of Neuchâtel is hosting an important part of EPFL's Microengineering Institute (IMT). This institute's research activities cover topics such as health, microsystems, photovoltaic and watchmaking. The installation of EPFL Neuchâtel campus, in 2013, is part of the EPFL's strategy to bring research activities closer to industrial interests at all stage of the innovation process. They benefit from the proximity of other research institutions and high-tech manufacturing societies active in micro- and nano-technologies and advanced manufacturing.

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KEYNOTE SPEAKERS



Prof. SHOJI KAWAHITO

Imaging Devices Laboratory, Research Institute of Electronics, Shizuoka University.

Ultra-Low-Noise Design of CMOS Image Sensors toward Photoelectron-Counting-Based Wide Dynamic Range Imaging

Tuesday, June 18th

09:00-09:45

Auditorium

Shoji Kawahito (F'09) received the Ph.D. degree from Tohoku University, Sendai, Japan, in 1988. He joined Tohoku University as a Research Associate in 1988. From 1989 to 1999, he was with the Toyohashi University of Technology, Toyohashi, Japan. From 1996 to 1997, he was a Visiting Professor with ETH Zurich, Zürich, Switzerland. Since 1999, he has been a Professor with the Research Institute of Electronics, Shizuoka University, Shizuoka, Japan. Since 2006, he has been the Chief Technology Officer of Brookman Technology Inc., Shizuoka, a university spin-off company for CMOS imager developments. He has authored over 300 papers in peer-reviewed journals and international conference proceedings. His current research interests include CMOS imaging devices, sensor interface circuits, and mixed analog/digital circuits designs. Dr. Kawahito is a fellow of the Institute of Image Information and Television Engineers and a member of the Institute of Electronics, Information and Communication Engineers (IEICE) and the International Society for Optics and Photonics. He has received plenty of awards, including the Outstanding Paper Award at the IEEE International Symposium on Multiple-Valued Logic in 1987, the Special Feature Award in LSI Design Contest at the Asia and South Pacific Design Automation Conference in 1998, the Beatrice Winner Award for Editorial Excellence at the IEEE International Solid-State Circuits Conference (ISSCC) in 2005, the IEICE Electronics Society Award in 2010, the Takayanagi Memorial Award in 2010, and the Walter Kosonocky Award in 2013. He served as a Technical Program Committee Member of ISSCC from 2009 to 2012, and the Program Committee Chair of the 2011 International Image Sensor Workshop. He was the Chair of the SSCS Japan Chapter from 2013 to 2014.

KEYNOTE SPEAKERS



Prof. ALPER DEMIR

Department of Electrical & Electronics Engineering, College of Engineering, Koç University.

Nonstationary Low Frequency Noise in Switched MOSFET Circuits and Circuit Simulation

Wednesday, June 19th

08:40-09:25

Auditorium

Alper Demir received the BS degree from Bilkent University in Turkey and the MS and PhD degrees from the University of California at Berkeley in the USA. Dr. Demir previously spent time at Motorola, Cadence Design Systems, Bell Laboratories Research, MIT, and UC Berkeley. He has been with Koç University in Istanbul as a faculty member since 2002. His work on noise won several best paper awards: 2002 Best of ICCAD Award, 2003 and 2014 IEEE/ACM William J. McCalla ICCAD Best Paper Awards, and the 2004 IEEE Circuits & Systems Society Guillemin-Cauer Award. He was named an IEEE Fellow in 2012 for his contributions to stochastic modelling and analysis of phase noise.

KEYNOTE SPEAKERS



Prof. ENRICO RUBIOLA

Université de Franche Comté & Department of Time and Frequency of the CNRS FEMTO-ST Institute, Besançon, France

The Origin and the Measurement of Phase Noise in Oscillators

Thursday, June 20th

09:00-09:45

Auditorium

Enrico Rubiola is full professor at the Université de Franche Comté and deputy director of the Department of Time and Frequency of the CNRS FEMTO-ST Institute, Besançon, France. Since 2012, he is the PI of the Oscillator IMP project, a platform for the measurement of short-term frequency stability and spectral purity. Formerly, he was a full professor at the Université Henri Poincaré, Nancy, France, a guest scientist at the NASA JPL, a guest professor at the Università di Parma, Italy, and an assistant professor at the Politecnico di Torino, Italy.

He graduated in electronic engineering at the Politecnico di Torino in 1983, received a Ph.D. in Metrology from the Italian Minister of University and Research, Roma (1989), and a Sc.D. degree from the Université de Franche Comté in 1999.

Enrico's interests are high-spectral purity oscillators from low RF to optics, general time and frequency metrology, phase noise, amplitude noise, noise in digital systems, frequency synthesis, spectral analysis, wavelet (Allan-like) variances, microwave photonics, precision electronics from dc to microwaves, and precision instrumentation. He has developed innovative instruments for AM/PM noise measurement with ultimate sensitivity, and a variety of dedicated signal-processing methods. He introduced the "Leeson effect" and "II and Λ frequency counters," and the full theory underneath, and he received the IEEE W. G. Cady Award (2018) for his contributions.

Enrico founded the European Frequency and Time Seminar (<http://efts.eu>) in 2013, and he has been chairing it since. A wealth of articles, reports, conference presentations, and lectures for PhD students and young scientists are available on the Enrico's home page <http://rubiola.org>.

KEYNOTE SPEAKERS



Prof. ALEXANDE BALANDIN

University of California, Riverside

Low-Frequency Noise in Low-Dimensional van der Waals Materials

Friday, June 21st

09:00-09:45

Auditorium

Alexander A. Balandin received his BS and MS degrees *Summa Cum Laude* in Applied Mathematics and Applied Physics from the Moscow Institute of Physics and Technology (MIPT), Russia. He received his second MS degree and PhD degree in Electrical Engineering from the University of Notre Dame, USA. From 1997 till 1999, he worked as a Research Engineer at the Department of Electrical Engineering, UCLA. In 1999 he joined UCR, where he is presently Distinguished Professor of Electrical and Computer Engineering, University of California Presidential Chair Professor of Materials Science, Director of the Phonon Optimized Engineered Materials (POEM) Center, Director of UCR Nanofabrication Facility, and Associate Director of DOE EFRC Spins and Heat in Nanoscale Electronic Systems (SHINES) Center. Professor Balandin is a Founding Chair of UCR campus-wide Materials Science and Engineering (MS&E) Program. His research expertise covers a wide range of nanotechnology, materials science, electronics, low-frequency noise, phononics and spintronics fields. He is recognized as a pioneer of the graphene thermal research field. His current research interests include charge-density-wave effects in two-dimensional materials and their device applications, low-frequency current fluctuations and electronic noise in materials and devices, Brillouin – Mandelstam and Raman spectroscopy of advanced materials, practical applications of graphene in thermal management, electronics and energy conversion. Professor Balandin is a recipient of The MRS Medal from the Materials Research Society, and *Pioneer of Nanotechnology Award* from IEEE Society for his graphene and nanotechnology research. He is an elected Fellow of eight professional societies: MRS, APS, IEEE, OSA, SPIE, IOP, IOM3 and AAAS. He is among the Clarivate Analytics and Thomson Reuters Highly Cited Researchers (Physics). He serves as Deputy Editor-in-Chief of the Applied Physics Letters. For more information, visit his group web-site: <http://balandingroup.ucr.edu/>

Conference Technical Program

Day 1

Session 1: Plenary 1	1
Ultra-Low-Noise Design of CMOS Image Sensors toward Photoelectron-Counting-Based Wide Dynamic Range Imaging <i>Shoji Kawahito</i>	1
Session 2A: Materials 1	2
Detection of Shot Noise in Solar Cells and LEDs Using Cross-Correlation Current Noise Spectroscopy <i>Kevin Davenport, Andrey Rogachev and Mark Hayward</i>	2
Low frequency noise deviation from Schottky theory in p-n junctions <i>Jean-Guy Tartarin, Jacques Graffeuil and Laurent Escotte</i>	6
Session 2B: Fundamental Theory 1	10
Low-Frequency Noise of Magnons <i>Sergey Rumyantsev, Michael Balinskiy, Fariborz Kargar, Alexander Khitun and Alexander Balandin</i>	10
Fluctuation -Dissipation-Dispersion Relation for Slow Processes and Quality Factor for Oscillation Systems <i>Viacheslav Belyi</i>	14
Session 3A: Devices and Materials 1	18
Charge carrier dynamics of strongly-correlated electrons in low-dimensional molecular metals studied by fluctuation spectroscopy <i>Jens Müller</i>	18
Lorentzian noise approach for 1D transport studies <i>M Petrychuk, I Zadorozhnyi, Yu Kutovyi, S Karg, H Riel and Svetlana Vitusevich</i>	19
Prehistory probability distribution of ion transition through graphene nanopore <i>Carlo Guardiani, William Gibby, Miroslav Barabash, Dmitry Luchinsky, Igor Khovanov and Peter McClintock</i>	23
Resistivity Characteristics and Noise Spectroscopy of Composites with Carbon Fiber Felts <i>Marina Tretjak, Sandra Pralgauskaitė, Jonas Matukas, Ieva Kranauskaitė, Jan Macutkevich, Jūras Banys, Vanessa Fierro, Alain Celzard and Blagoj Karakashov</i>	27
Session 3B: Fundamental Theory 2	31
Noise-induced nonlinear dynamics of high Q nanomechanical resonators <i>Eva M. Weig</i>	31
Analysis of the ultimate noise performance of a mesoscopic cavity magnetic sensor <i>Massimo Macucci and Paolo Marconcini</i>	32
An Itô-Stratonovich dilemma-free treatment for nonlinear oscillators with colored noise <i>Michele Bonnin, Fabrizio Bonani and Fabio Traversa</i>	36
Session 4A: Fundamental Theory 3	40
Design and realization of ultra-low noise cryoHEMTs for cryogenic readout electronics <i>Yong Jin, Quan Dong, Laurent Couraud, Antonella Cavanna, Ulf Gennser, Christian Ulysse and Edmond Cambril</i>	40
Shot noise and squeezing in the conduction channel of a Field Effect Transistor at ultra-low temperature <i>Anthoni Manseau, Édouard Pinsolle, Christian Lupien and Bertrand Reulet</i>	41
Discussion of the flicker noise origin at very low temperature and polarisation operation <i>Dimitri Boudier, Bogdan Cretu, Eddy Simoen, Anabela Veloso and Cor Claeys</i>	45
Generation-recombination noise of magnetic monopoles in spin ice <i>Alexey Klyuev, Mikhail Ryzhkin and Arkady Yakimov</i>	49

Session 4B: Fundamental Theory and Materials 1	52
Electronic noise due to temperature differences across nanoscale conductors: beyond standard thermal and shot noises	
<i>Oren Tal</i>	52
Magneto-Electric Diffusion of Electrons in Gallium Nitride: a Monte Carlo Analysis	
<i>Galina Syngayivska, Vadym Korotyeyev, Viacheslav Kochelap and Luca Varani</i>	53
Probabilistic analysis of two models of ideal memristor with external noise	
<i>Anna Kharheva, Alexander Dubkov and Bernardo Spagnolo</i>	57
Noise-delayed decay for Levy flights in unstable parabolic potential	
<i>Alexander Dubkov, Bartłomiej Dybiec, Bernardo Spagnolo and Davide Valenti</i>	61
Session 5A: Devices 2	65
RF Noise Benchmark Tests for MOSFETs	
<i>Andries J. Scholten, Gert-Jan Smit, Ralf M. T. Pijper and Luuk F. Tiemeijer</i>	65
1/f Noise in Fully Integrated Electrolytically Gated FinFETs with Fin Width Down to 20nm	
<i>Koen Martens, Bert Du Bois, Yong Kong Siew, Anshul Gupta, Anabela Veloso, Emmanuel Dupuy, Dunja Radisic, Efrain Altamirano Sanchez, Willem Van Roy, Simone Severi and Eddy Simoen</i>	66
Processing Impact on the Low-Frequency Noise of 1.8 V Input-Output Bulk FinFETs	
<i>Cor Claeys, Geert Hellings, Hiroaki Arimura, Bertrand Parvais, Lars-Åke Ragnarsson, Harold Dekkers, Tom Schram, Dimitri Linten, Naoto Horiguchi, Eddy Simoen, Dimitri Boudier and Bogdan Cretu</i>	69
A 4-Terminal Method for Oxide and Semiconductor Trap Characterization in FDSOI MOSFETs	
<i>Hung Chi Han, Christoforos Theodorou and Gerard Ghibaudo</i>	73
Session 5B: Biological Systems 1	77
Low-Frequency Noise in Electrochemical Sensors for Water Quality Monitoring	
<i>Arif Ul Alam, Sumit Majumder, Ching-Hung Chen, Ognian Marinov and Jamal Deen</i>	77
Nanoimprint technology for liquid-gated Si nanowire FET biosensors: Noise spectroscopy analysis	
<i>V Handziuk, Yu Kutovyi, H Hlukhova, I Zadorozhnyi, N Boichuk, M Petrychuk and Svetlana Vitusevich</i>	83
Ascorbate Detection Using Single Trap Phenomena in Two-Layer Si NW FETs	
<i>Yurii Kutovyi, Ihor Zadorozhnyi, Natalia Naumova, Nazarii Boichuk, Mykhaylo Petrychuk and Svetlana Vitusevich</i>	87
Noise in Single-Trap Punctual Nanobiosensors	
<i>Ihor Zadorozhnyi, Yurii Kutovyi, Soo Hyeon Kim, Teruo Fujii, Andreas Offenhäusser, Svetlana Vitusevich and Nicolas Clément</i>	91
Day 2	
Session 6: Plenary 2	95
Nonstationary Low Frequency Noise in Switched MOSFET Circuits and Circuit Simulation	
<i>A. Gokcen Mahmutoglu and Alper Demir</i>	95
Session 7A: Devices 3	99
Reduction of the Low Frequency Noise and Negative Photoconductivity in HgTe Quantum Wells	
<i>Sergey Rumyantsev, Ivan Yahniuk, Dmytro But, Grzegorz Cywinski, Bartłomiej Grzywacz, Nikolay Mikhailov, Sergey Dvoretzky, Jerzy Łusakowski and Wojciech Knap</i>	99
Micromagnetic Modeling of Telegraphic Mode Jumping in Microwave Spin Torque Oscillators	
<i>Gunnar Malm, Anders Eklund and Mykola Dvornik</i>	103
Detection of high frequency cyclostationary third moment of current fluctuations in a tunnel junction	
<i>Pierre Fevrier, Christian Lupien and Bertrand Reulet</i>	107
Shot-noise of high-impedance quantum devices using impedance matching	
<i>Christian Schoenenberger, Thomas Hasler, Gabriel Puebla-Hellmann, Vishal Ranjan, Cezar Harabula, Roy Haller, Minkyung Jung and Gergö Fülöp</i>	111
Session 7B: Fundamental Theory 4	112
Fluctuation analysis of repetitive writing motion by using DFA	
<i>Masafumi Uchida</i>	112
Making the eavesdropper's life harder	
<i>Gergely Vadai and Laszlo Kish</i>	116
Randomness assists in wireless connectivity	
<i>Sumit Kumar, Taniya Singh, Rajib Jha and Mohammad Akhlaqur Rahman</i>	120
Noise Injection/machine learning Fraud Detection Framework in Time Series Data	
<i>Aristidis Magklaras, Nikolaos Andriopoulos and Alexios Birbas</i>	124

Session 8: Poster Session A	128
Dynamic Stochastic Resonance Based Blocking Artifacts Removal from Compressed Images in DCT Domain <i>Rajib Jha , Pramod Kumar Tiwari, Onkar Krishna, Jawar Singh and Saurabh Kumar Pandey</i>	128
Atomistic model of reptation at polymer interfaces <i>Dmitry Luchinsky , Halyna Hafiychuk, Miroslav Barabash, Vasyl Hafiychuk, Kevin Wheeler, Peter McClintock and Taku Ozawa</i>	132
Determination of activation energies of oxygen ion diffusion in memristor systems from the flicker noise spectrum <i>Alexey Klyuev, Arkady Yakimov, Dmitry Filatov, Oleg Gorshkov, Dmitry Antonov, Dmitry Liskin, Ivan Antonov and Yulia Anikina</i>	136
Coherent and Conventional Gravidynamic Quantum 1/f Effects <i>Peter H Handel</i>	140
Session 9A: Materials 2	144
Noise in Diffusive Conductor <i>Edouard Pinsolle, Samuel Houle, Christian Lupien and Bertrand Reulet</i>	144
Fluctuation Scaling in Nano-Interconnects and its Application to Electromigration <i>Sofie Beyne and Tim Beyne</i>	148
Finite frequency noise: an original probe for topological superconductors <i>Jerome Rech, Didier Bathellier, Laurent Raymond, Thibaut Jonckheere, Alex Zazunov and Thierry Martin</i>	152
Noise Measurements on MnSi thin films <i>Merlin Mitschek, David Schroeter, Dirk Menzel, Stefan Süllo and Jens Müller</i>	156
Session 9B: Circuits 1	160
LFN and RTN in Nanoscale Devices: Modeling and Impact on Circuit Operation <i>Christoforos Theodorou and Gerard Ghibaudo</i>	160
In-situ noise system measurement for SiGe HBT characterization at 150 GHz <i>Simon Bouvot, Joao Carlos Azevedo Gonçalves, Thomas Quémerais, Daniel Gloria, Guillaume Ducournau, Sylvie Lépilliet and François Danneville</i>	164
Integrated W-Band Measurement System Combining IMD, S-Parameters and Noise Figure Suitable for Coax, Waveguide and On-Wafer Test <i>Joel Dunsmore and Suren Singh</i>	168
Analysis on Noise Requirements of RF Front-End Circuits for Spin Qubit Readout <i>Yatao Peng, Andrea Ruffino and Edoardo Charbon</i>	172
Session 10A: Devices 4	176
Contact effects, Stability and Noise Investigation in Organic Thin-Film Transistors <i>Gino Giusi , Graziella Scandurra, Sabrina Calvi, Guglielmo Fortunato, Matteo Rapisarda, Luigi Mariucci and Carmine Ciofi</i>	176
Low frequency noise characterization of Si Nanonet Field Effect Transistors <i>Thibault Cazimajou, Christoforos Theodorou, Mireille Mouis, Thi Thu Thuy Nguyen, Maxime Legallais, Céline Ternon and Gérard Ghibaudo</i>	180
A cost-competitive low Noise Junction-FET (JFET) for high precision Analog Application <i>Qiang Ai , Suba Subramaniam , Michaelina Ong and Manoj Chandrika</i>	184
Low-frequency noise behavior of nMOSFETs with different Al₂O₃ capping layer thickness and TiN gate <i>Danghui Wang, Eddy Simoen, Cor Claeys, Bogdan Govoreanu, Stefan Kubicek, Julien Jussot, B.T. Chan, Nard Dumoulin-Stuyck, Iuliana Radu and Dan Mocuta</i>	188
Session 10B: Biological Systems 2	192
Noise in Interacting Biological Systems <i>Tomislav Stankovski, Peter McClintock and Aneta Stefanovska</i>	192
Parameter change of propagating waves in dominant arms and non-dominant arms using multichannel surface electrogram <i>Marzieh Aliabadi Farahani, Miki Haruna, Kota Akehi, Kazuyuki Mito, Tota Mizuno and Naoaki Itakura</i>	196
Method to extract latent semantic components from noisy categorical time-series data applied to human sleep stage data <i>Ikuhiro Yamaguchi, Akifumi Kishi, Fumiharu Togo and Yoshiharu Yamamoto</i>	200
Diffusion noise as a tool for in-vitro investigation of interacting biomolecules <i>Mathias Lechelon, Matteo Gori, Marco Pettini, Yoann Meriguet, Anastasiia Kudashova, Marlon Sidore, Jeremie Torres and Luca Varani</i>	204

Session 11: Poster Session B	208
Study of Low Frequency Noise Parameters of Metal Contacts	
<i>Alexander Ermachikhin, Vladimir Litvinov, Tatiana Kholomina, Nikolay Rybin, Andrey Semenov, Loginov and Krutchenko</i>	208
An FPGA Based Practical Implementation of Stochastic Resonance For Image Enhancement	
<i>Sumit Kumar, Sudha Chauhan and Rajib Jha</i>	212
Cosmic Nonstationarity of the Coherent Gravidynamic Quantum 1/f Effect	
<i>Peter H Handel and Erika Splett</i>	216
Temporal stability measurements of a cooled infrared type II superlattice (T2SL) focal plane array detector	
<i>Vignesh Arounassalame, Jean Nghiem, Maxence Guenin, Eric Costard, Philippe Christol and Isabelle Ribet-Mohamed</i>	220
Characterization methods of low frequency RTS noise in HgCdTe infrared detectors	
<i>Maxence Guénin, Sophie Derelle, Marcel Caes, Laurent Rubaldo and Isabelle Ribet-Mohamed</i>	224
Session 12A: Circuits and DSP 1	228
Pulse Detection with a Multi-state System	
<i>Roy Howard</i>	228
Noise and Linearity of High-Speed SiGe HBT Cells in CE and CB Configuration	
<i>Paulius Sakalas, Anindya Mukherjee and Michael Schroter</i>	232
Implementing software defined noise generators	
<i>Robert Mingesz and Dénes Faragó</i>	236
Radon Transform and Dynamic Stochastic Resonance based Technique for Line Detection from Noisy Images	
<i>Rajib Kumar Jha and Badal Soni</i>	240
Suprathreshold Stochastic Resonance for Gamma Noise with Watermarking Application	
<i>Sumit Kumar, Nancy Chauhan and Rajib Jha</i>	244
Session 12B: Biological Systems 3	248
Effect of Clustering on the Fluctuation in Binding Activity of Sugar Chains to Influenza Viruses	
<i>Toshio Kawahara</i>	248
Statistical theory of mixed-valence selectivity in biological ion channels	
<i>William Gibby, Miraslau Barabash, Carlo Guardiani, Dmitry Luchninsky and Peter McClintock</i>	252
Interplay between channel and shot noise in subthreshold voltage fluctuations of neural membranes	
<i>Beatriz G. Vasallo, Javier Mateos and Tomás González</i>	256
1/f DNA Hydrogen-Bond Energy Noise	
<i>Nazarii Boichuk, Yurii Kutovyi, Nicolas Lobato-Dauzier, Anthony Genot, Teruo Fujii, Andreas Offenhäusser, Svetlana Vitusevich and Nicolas Clément</i>	260
The dynamics of quasiparticles in the KcsA biological ion channel	
<i>Miraslau L. Barabash, William A.T. Gibby, Dmitry G. Luchinsky, Carlo Guardiani, Igor A. Khovanov and Peter V.E. McClintock</i>	264
 Day 3	
 Session 13: Plenary 3	 268
The Origin and the Measurement of Phase Noise in Oscillators	
<i>Enrico Rubiola</i>	268
Session 14A: Material 3	269
Noise spectroscopy-based gas identifying methods to improve the selectivity of MOX gas sensors.	
<i>Thierry Contaret, Nicolas Morati, Sami Gomri, Tomas Fiorido, Jean-Luc Seguin and Marc Bendahan</i>	269
Bulk induced 1/f noise in topological insulators	
<i>Saurav Islam, Semonti Bhattacharyya, Hariharan Nhalil, Anthony Richardella, Abhinav Kandala, Nitin Samarth and Arindam Ghosh</i>	273
Trapping Investigation of the GaN HEMT Devices Using the Low Frequency Noise Characterization	
<i>Mohamed Bouslama, Jean-Christophe Nallatamby and Michel Prigent</i>	274
Session 14B: Fundamental Theory 5	278
1/f Noise Generated with the Branching Process Model	
<i>Takayuki Kobayashi</i>	278
Thomson Scattering in Inhomogeneous Plasmas: The Role of the Fluctuation-Dissipation Theorem	
<i>Viacheslav Belyi</i>	282
Quantum 1/f Noise –a Decoherence Phenomenon	
<i>Peter H Handel</i>	286

Session 15: Poster Session C	290
Low frequency noise of GaSb layers on GaAs substrate	
<i>Lukasz Ciura, Andrzej Kolek, Krzysztof Czuba, Iwona Sankowska and Agata Jasik</i>	290
Using the velocity auto-correlation function to characterize functional "noise" in bio-molecules	
<i>Marlon Sidore, Yoann Meriguet, Anastasiia Kudashova, Mathias Lechelon, Matteo Gori, Marco Pettini, Jeremie Torres and Luca Varani</i>	294
Energy and Area Aware Digital Fingerprint Generator Using Intrinsic Randomness	
<i>Jawar Singh, Sandeepkumar Pandey, Rajib Kumar Jha and Pramod K Tiwari</i>	298
Effects of mechanical stress on electrical parameters and noise of supercapacitors	
<i>Arkadiusz Szewczyk, Łukasz Lentka and Janusz Smulko</i>	302
Session 16A: Devices and Noise Measurements 1	306
Noise in electrical double-layer capacitors (EDLCs)	
<i>Janusz Smulko, Arkadiusz Szewczyk and Łukasz Lentka</i>	306
Ultra-low noise, single JFET voltage pre-amplifier for low frequency noise measurements	
<i>Graziella Scandurra, Carmine Ciofi and Gino Giusi</i>	310
Low frequency noise characterization and modeling of SiGe HBT featuring LASER annealing in a 55-nm CMOS node	
<i>Johnny El Beyrouthy, Alexandre Vauthelin, Bruno Sagnes, Fabien Pascal, Alain Hoffmann, Matteo Valenza, Sébastien Haendler, Alexis Gauthier, Pascal Chevalier and Daniel Gloria</i>	314
Low-Frequency Noise in InGaZnO Thin-Film Transistors with Al₂O₃ Gate Dielectric	
<i>Horacio Londono, Yu-Chieh Chien, Luis Hoffman, Manoj Nag, Sebastian Haesler, Soeren Steudel and Jan Genoe</i>	318
Session 16B: Devices and Materials 2	322
Adhesive Low Frequency Noise (LFN) in Charge Trap Transistors (CTT) for Neuromorphic Analog Processing	
<i>Alexios Birbas</i>	322
Low-frequency noise considerations for sensors based on manganites	
<i>Bruno Guillet, Ammar Aryan, Luiz Enger, Stéphane Flament, Marc Lam Chok Sing, Sylvain Lebargy, Shuang Liu, Laurence Méchin, Vanuza Nascimento Marques, Olivier Rousseau, Jean-Marc Routoure and Sheng Wu</i>	326
Low Noise Characteristics of Schottky Diode with Deep Energy Level	
<i>Alexander Ermachikhin, Vladimir Litvinov, Tatiana Kholomina and Andrey Semenov</i>	330
Day 4	
<hr/>	
Session 17: Plenary 4	334
Low-Frequency Noise in Low -Dimensional van der Waals Materials	
<i>Alexander Balandin and Sergey Rumyantsev</i>	334
Session 18A: Devices and Circuits 1	338
Thermodynamics limits in Oscillators and Phase Locked Loops	
<i>Armina Khakpour and Antonio Liscidini</i>	338
Statistics of low-frequency noise in MOSFETs	
<i>Andries J. Scholten, Thiago H. Both, Maurício Banaszkeski da Silva, Gilson I. Wirth, Hans P. Tuinhout, Adrie T. A. Zegers-van Duijnhoven and Jeroen A. Croon</i>	342
Random Telegraph Signal Fluctuations of Dark Count Rate in CMOS SPAD Structures	
<i>Francesco Di Capua, Daniela Fiore, Marcello Campajola, Ettore Sarnelli and Ciro Nappi</i>	343
A kTC Noise Analysis in a Passive Switched-Capacitor Correlated Multiple Sampling Circuit for CIS	
<i>Raffaele Capoccia, Assim Boukhayma and Christian Enz</i>	348
Session 18B: Devices and Optoelectronics 1	352
Nanoscopy of charge kinetics via terahertz fluctuation	
<i>Qianchun Weng, Zhenghua An, Wei Lu and Susumu Komiyama</i>	352
Low Frequency Noise Spectroscopy of GaN Bow-Tie THz Detectors	
<i>Sandra Pralgauskaitė, Jonas Matukas, Evaldas Kažukauskas, Irmantas Kašalynas, Vytautas Janonis and Paweł Prystawko</i>	353
1/f noise model of 980 nm InGaAs/GaAs laser diodes based on parasitic parameters under low injection current	
<i>Xiaojuan Chen and Chang Qu</i>	357